Power MOSFET -2.3 Amps, -16 Volts

Dual SOIC-8 Package

Features

- High Efficiency Components in a Single SOIC-8 Package
- High Density Power MOSFET with Low R_{DS(on)}
- Logic Level Gate Drive
- SOIC-8 Surface Mount Package, Mounting Information for SOIC-8 Package Provided
- Pb–Free Packages are Available

Applications

• Power Management in Portable and Battery–Powered Products, i.e.: Computers, Printers, PCMCIA Cards, Cellular and Cordless Telephones

MAXIMUM RATINGS (T_J = 25°C unless otherwise noted)

Rating	Symbol	Value	Unit
Drain-to-Source Voltage	V _{DSS}	-16	V
Gate-to-Source Voltage - Continuous	V _{GS}	±10	V
Thermal Resistance – Junction–to–Ambient (Note 1) Total Power Dissipation @ $T_A = 25^{\circ}C$ Continuous Drain Current @ $T_A = 25^{\circ}C$ Continuous Drain Current @ $T_A = 100^{\circ}C$ Pulsed Drain Current (Note 4)	R _{θJA} P _D I _D I _D I _{DM}	175 0.71 -2.3 -1.45 -9.0	°C/W W A A A
Thermal Resistance – Junction–to–Ambient (Note 2) Total Power Dissipation @ $T_A = 25^{\circ}C$ Continuous Drain Current @ $T_A = 25^{\circ}C$ Continuous Drain Current @ $T_A = 100^{\circ}C$ Pulsed Drain Current (Note 4)	R _{θJA} P _D I _D I _D I _{DM}	105 1.19 -2.97 -1.88 -12	°C/W W A A A
Thermal Resistance – Junction–to–Ambient (Note 3) Total Power Dissipation @ $T_A = 25^{\circ}C$ Continuous Drain Current @ $T_A = 25^{\circ}C$ Continuous Drain Current @ $T_A = 100^{\circ}C$ Pulsed Drain Current (Note 4)	R _{θJA} P _D I _D I _D I _{DM}	62.5 2.0 -3.85 -2.43 -15	°C/W W A A A
Operating and Storage Temperature Range	T _J , T _{stg}	– 55 to +150	°C
Single Pulse Drain-to-Source Avalanche Energy – Starting T _J = 25° C (V _{DD} = -16 Vdc, V _{GS} = -4.5 Vdc, Peak I _L = -5.0 Apk, L = 28 mH, R _G = 25 Ω)	E _{AS}	350	mJ
Maximum Lead Temperature for Soldering Purposes, 1/8" from case for 10 seconds	TL	260	°C

Maximum ratings are those values beyond which device damage can occur. Maximum ratings applied to the device are individual stress limit values (not normal operating conditions) and are not valid simultaneously. If these limits are exceeded, device functional operation is not implied, damage may occur and reliability may be affected.

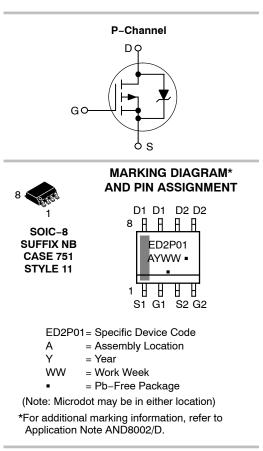
- 1. Minimum FR-4 or G-10 PCB, Steady State.
- Mounted onto a 2" square FR-4 Board (1 in sq, 2 oz Cu 0.06" thick single sided), Steady State.
- 3. Mounted onto a 2" square FR-4 Board (1 in sq, 2 oz Cu 0.06" thick single sided), t \leq 10 seconds.
- 4. Pulse Test: Pulse Width = $300 \ \mu$ s, Duty Cycle = 2%.



ON Semiconductor®

http://onsemi.com

V _{DSS}	R _{DS(ON)} Тур	I _D Max
–16 V	100 mΩ @ −4.5 V	–2.3 A



ORDERING INFORMATION

Device		Package	Shipping [†]
NTMD2P01	R2	SOIC-8	2500/Tape & Reel
NTMD2P01	R2G	SOIC-8 (Pb-Free)	2500/Tape & Reel

⁺For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D

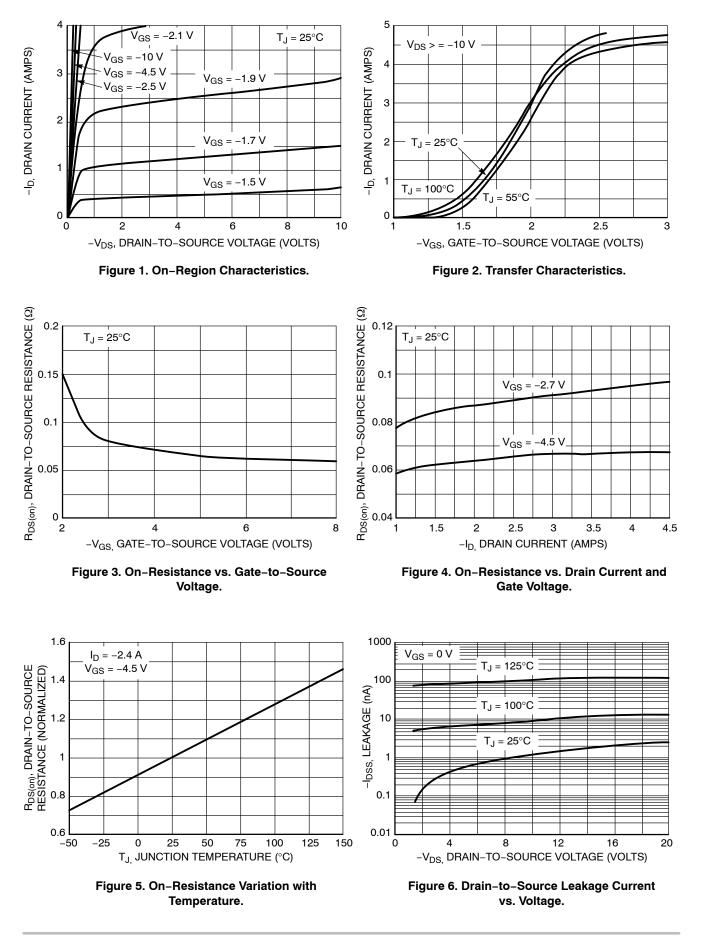
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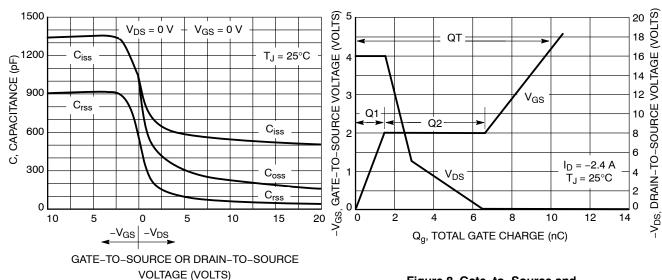
Downloaded from Elcodis.com electronic components distributor

ELECTRICAL CHARACTERISTICS (T_J = 25° C unless otherwise noted) (Note 5)

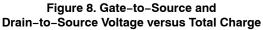
Characteristic			Min	Тур	Max	Unit
OFF CHARACTERISTICS						
Drain-to-Source Breakdown Voltage						Vdc
$(V_{GS} = 0 \text{ Vdc}, I_D = -250 \ \mu \text{Adc})$ Temperature Coefficient (Positive)			-16 -	-12.7	-	mV/°C
Zero Gate Voltage Drain Current ($V_{DS} = -16$ Vdc, $V_{GS} = 0$ Vdc, T	u − 25°C)	I _{DSS}	_	_	-1.0	μAdc
$(V_{DS} = -16 \text{ Vdc}, V_{GS} = 0 \text{ Vdc}, T$ $(V_{DS} = -16 \text{ Vdc}, V_{GS} = 0 \text{ Vdc}, T$			-	-	-10	
Gate-Body Leakage Current (V _{GS} = -10 Vdc, V _{DS} = 0 Vdc)			_	_	-100	nAdc
Gate–Body Leakage Current (V _{GS} = +10 Vdc, V _{DS} = 0 Vdc)			10		100	nAdc
ON CHARACTERISTICS				•		
Gate Threshold Voltage		V _{GS(th)}	<u> </u>		. –	Vdc
$(V_{DS} = V_{GS}, I_D = -250 \ \mu Adc)$ Temperature Coefficient (Negative)			-0.5 -	-0.90 2.5	-1.5 -	mV/°C
Static Drain-to-Source On-State R	lesistance	R _{DS(on)}		1		Ω
$(V_{GS} = -4.5 \text{ Vdc}, I_D = -2.4 \text{ Adc})$ $(V_{GS} = -2.7 \text{ Vdc}, I_D = -1.2 \text{ Adc})$		· · /	-	0.070 0.100	0.100 0.130	
$(V_{GS} = -2.5 \text{ Vdc}, I_D = -1.2 \text{ Adc})$			-	0.110	0.150	
Forward Transconductance (V _{DS} = -10 Vdc, I _D = -1.2 Adc)			-	4.2	_	Mhos
DYNAMIC CHARACTERISTICS		l.		•		
Input Capacitance		C _{iss}	_	540	750	pF
Output Capacitance	(V _{DS} = −16 Vdc, V _{GS} = 0 Vdc, f = 1.0 MHz)	C _{oss}	-	215	325	
Reverse Transfer Capacitance		C _{rss}	-	100	175	
SWITCHING CHARACTERISTICS (Notes 6 and 7)				•	
Turn-On Delay Time		t _{d(on)}	-	10	20	ns
Rise Time	$(V_{DD} = -10 \text{ Vdc}, I_D = -2.4 \text{ Adc},$	t _r	-	35	65	
Turn-Off Delay Time	$V_{GS} = -4.5$ Vdc, $R_G = 6.0 \Omega$)	t _{d(off)}	-	33	60	
Fall Time		t _f	-	29	55	
Turn-On Delay Time		t _{d(on)}	-	15	-	ns
Rise Time	(V _{DD} = -10 Vdc, I _D = -1.2 Adc,	t _r	-	40	_	
Turn-Off Delay Time	$V_{GS} = -2.7 \text{ Vdc},$ $R_G = 6.0 \Omega)$	t _{d(off)}	-	35	_	
Fall Time		t _f	_	35	_	-
Total Gate Charge		Q _{tot}	_	10	18	nC
Gate-Source Charge	− (V _{DS} = −16 Vdc, V _{GS} = −4.5 Vdc,	Q _{gs}	_	1.5	_	1
Gate-Drain Charge	$I_D = -2.4 \text{ Adc}$	Q _{gd}	_	5.0	_	
BODY-DRAIN DIODE RATINGS (N	ote 6)	5	L	1	I	1
Diode Forward On-Voltage		V _{SD}		-0.88 -0.75	-1.0 -	Vdc
Reverse Recovery Time		t _{rr}	_	37	-	ns
-	$(I_{S} = -2.4 \text{ Adc}, V_{GS} = 0 \text{ Vdc},$	ta	_	16	_	-
	dI _S /dt = 100 A/µs)	t _b	_	21	_	-
Reverse Recovery Stored Charge						

5. Handling precautions to protect against electrostatic discharge is mandatory. 6. Indicates Pulse Test: Pulse Width = $300 \ \mu s \ max$, Duty Cycle = 2%. 7. Switching characteristics are independent of operating junction temperature.









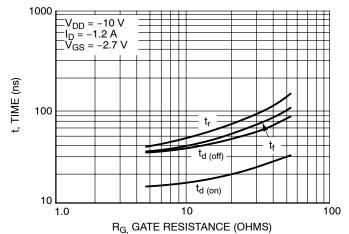
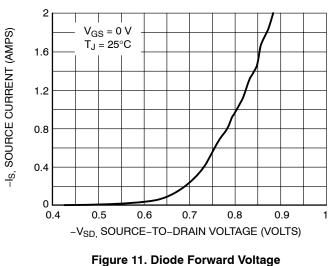


Figure 9. Resistive Switching Time Variation versus Gate Resistance



versus Current

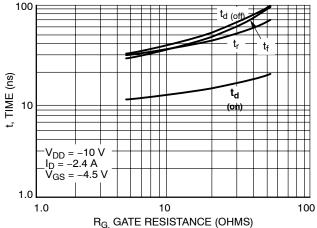
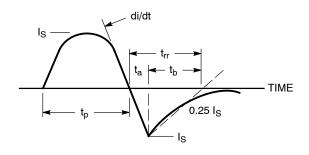


Figure 10. Resistive Switching Time Variation versus Gate Resistance





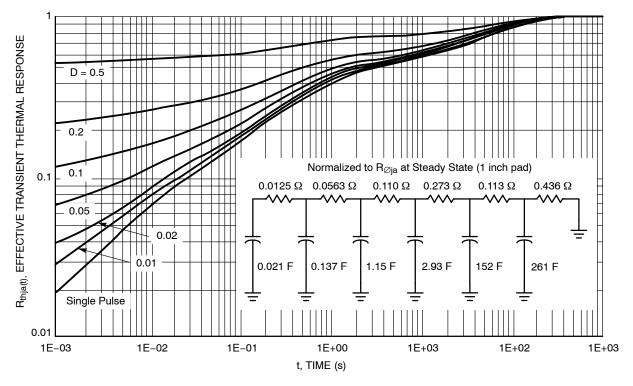
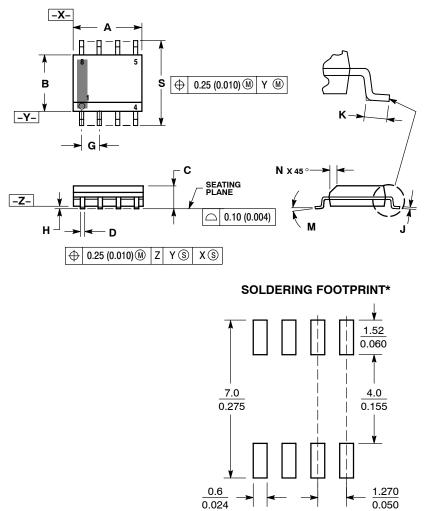


Figure 13. FET Thermal Response

PACKAGE DIMENSIONS

SOIC-8 NB CASE 751-07

ISSUE AG



NOTES:

- DIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 1982.
- CONTROLLING DIMENSION: MILLIMETER.
 DIMENSION A AND B DO NOT INCLUDE
- MOLD PROTRUSION. 4. MAXIMUM MOLD PROTRUSION 0.15 (0.006)
- PER SIDE. 5. DIMENSION D DOES NOT INCLUDE DAMBAR PROTRUSION. ALLOWABLE DAMBAR PROTRUSION SHALL BE 0.127 (0.005) TOTAL
- IN EXCESS OF THE D DIMENSION AT MAXIMUM MATERIAL CONDITION. 6. 751-01 THRU 751-06 ARE OBSOLETE. NEW
- 51-01 THRU 751-06 ARE OBSOLETE. NEV STANDARD IS 751-07.

	MILLIMETERS		INC	HES	
DIM	MIN	MAX	MIN	MAX	
Α	4.80	5.00	0.189	0.197	
в	3.80	4.00	0.150	0.157	
С	1.35	1.75	0.053	0.069	
D	0.33	0.51	0.013	0.020	
G	1.27 BSC		0.050 BSC		
Н	0.10	0.25	0.004	0.010	
ſ	0.19	0.25	0.007	0.010	
κ	0.40	1.27	0.016	0.050	
Μ	0 °	8 °	0 °	8 °	
Ν	0.25	0.50	0.010	0.020	
s	5.80	6.20	0.228	0.244	
STVLE 11					

STYLE 11: PIN 1. SOURCE 1 2. GATE 1 3. SOURCE 2

- 4. GATE 2
- 5. DRAIN 2 6. DRAIN 2
- DRAIN 2
 DRAIN 1
- 8. DRAIN 1

*For additional information on our Pb–Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

 $\left(\frac{\text{mm}}{\text{inches}}\right)$

SCALE 6:1

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